GQM Series Specifications and Test Methods

No.	o. Item		Specifications	Test Method					
1	Operating Temperature		–55 to 125℃	Reference Temperature: 25°C					
2	Rated Voltage		See the previous page.	The rated voltage is defined as the maximum voltage which may be applied continuously to the capacitor. When AC voltage is superimposed on DC voltage, V ^{P-P} or V ^{O-P} , whichever is larger, should be maintained within the rated voltage range.					
3	Appearance		No defects or abnormalities	Visual inspection					
4	Dimensio	n	Within the specified dimensions	Using calipers					
5	Dielectric Strength		No defects or abnormalities	No failure should be observed when 300%* of the rated voltage is applied between the terminations for 1 to 5 seconds, provided the charge/discharge current is less than 50mA. *GQM187, GQM219(250V), GQM22: 250% of the rated voltage					
6	Insulation Resistance		More than 10,000M Ω	The insulation resistance should be measured with a DC voltage not exceeding the rated voltage at 25℃ and 75%RH max. and within 2 minutes of charging, provided the charge/discharge current is less than 50mA.					
7	Capacita	nce	Within the specified tolerance	The capacitance/Q should be measured at 25°C at the					
	Q		30pF and over: Q≧1400	frequency and voltag	e shown in t	he table.			
8			30pF and below: Q≧800+20C	Frequency		1±0.1MHz			
_			C: Nominal Capacitance (pF)	Voltage		0.5 to 5Vrm	5		
	Temperatu Coefficient		Within the specified tolerance (Table A)	The capacitance char each specified temp.	-	e measured af	ter 5 min. at		
9	Capacitance Temperature Characteristics	Capacitance Drift	Within $\pm 0.2\%$ or ± 0.05 pF (Whichever is larger)	The temperature coefficient is determined using the capacitance measured in step 3 as a reference. When cycling the temperature sequentially from step 1 through 5 the capacitance should be within the specified tolerance for the temperature coefficient and capacitance change as Table A. The capacitance drift is calculated by dividing the differences between the maximum and minimum measured values in the steps 1, 3 and 5 by the capacitance value in step 3. Step Temperature (°C) 1 Reference Temp. ±2 2 —55±3 3 Reference Temp. ±2					
				5	125±3 Reference Temp. ±2				
10	Adhesive Strength of Termination		minotion		Solder the capacitor to the test jig (glass epoxy board) shown in Fig. 1 using a eutectic solder. Then apply 10N* force in parallel with the test jig for 10±1 sec. The soldering should be done either with an iron or using the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock. *5N (GQM188)				
				Type GQM18	а	b	С		
					1.0	3.0 4.0	1.2		
			Solder resist	GQM21 GQM22	2.2	5.0	<u>1.65</u> 2.9		
			Baked electrode or copper foil	(in mm) Fig. 1					
		Appearance	No defects or abnormalities	Solder the capacitor to the test jig (glass epoxy board) in the same manner and under the same conditions as (10). The capacitor should be subjected to a simple harmonic motion having a total amplitude of 1.5mm, the frequency being varied uniformly between the approximate limits of 10 and 55Hz. The frequency range, from 10 to 55Hz and return to 10Hz, should be traversed in approximately 1 minute. This motion should be applied for a period of 2 hours in each of 3 mutually perpendicular directions (total of 6 hours).					
		Capacitance	Within the specified tolerance						
11	Vibration Resistance	Q	30pF and over: Q≥1400 30pF and below: Q≥800+20C C: Nominal Capacitance (pF)						

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No.	Ite	em		Specific	ations			Tes	st Metho	d			
•0.	110		·			Solder the capacitor on the test jig (glass epoxy board) shown in Fig. 2 using a eutectic solder.							
12		Appearance	No defects or abnormalities. Within ±5% or ±0.5pF										
		Capacitance Change	(Whichever is large	•			Then apply a	Then apply a force in the direction shown in Fig. 3.					
	Deflection		04.5 100 t: 1.6mm			The soldering should be done by the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock. 20 50 Pressurizing speed: 1.0mm/sec. Pressurize							
			Tuno o h o					-	flexure : ≦1				
			Type GQM18	1.0	3.0	1.2		I L	<i></i>				
			GQM21	1.2	4.0	1.65		Capacitar					
			GQM22	2.2	5.0	2.9		45	45	-			
				Fig.	2	(in mm)		Fig.	3				
							Immerse the capacitor in a solution of ethanol (JIS-K-8101) and				(-8101) and		
13	Solderab Terminati	•	75% of the terminations are to be soldered evenly and continuously.			rosin (JIS-K-5902) (25% rosin in weight proportion). Preheat a 80 to 120°C for 10 to 30 seconds. After preheating, immerse in eutectic solder solution for 2±0.5 seconds at 230±5°C or Sn-3.0Ag-0.5Cu solder solution for 2±0.5 seconds at 245±5°			Preheat at mmerse in ℃ or				
			The measured and specifications in the			ould satisfy the							
		Appearance	No defects or abno	ormalities.									
14	Resistance to Soldering Heat	Capacitance Change	Within ±2.5% or ± (Whichever is large				Preheat the capacitor at 120 to 150°C for 1 minute. It capacitor in a eutectic solder or Sn-3.0Ag-0.5Cu sol at 270±5°C for 10±0.5 seconds. Let sit at room temp 24±2 hours, then measure.			mmerse the			
		Q	30pF and over: Q≧ 30pF and below: C										
			C: Nominal Capac	itance (pF)									
		I.R.	More than 10,000N	ΛΩ									
		Dielectric Strength	No defects.										
			The measured and specifications in the			ould satisfy the							
		Appearance	No defects or abno	ormalities.						in the same ma	anner and		
	Temperature	Capacitance Change	Within ±2.5% or ± (Whichever is large				 under the same conditions as (10). Perform the five cycles according to the four heat treat listed in the following table. 			atments			
15			30pF and over: Q≧1400		Let sit for 24±	2 hours at roo	m tempe	rature, then me	asure.				
. •	Cycle	Q	30pF and below: C	ì≥800+20C			Step	1	2	3	4		
		2	C: Nominal Capaci	itance (pF)			Temp. (℃)	Min. Operating Temp. +0/-3	Room Temp.	Max. Operating Temp. +3/-0	Room Temp.		
		I.R.	More than 10,000N	· · · · · · · · · · · · · · · · · · ·			Time (min.)	30±3	2 to 3	30±3	2 to 3		
		Dielectric Strength	No defects.										
16	2g		The measured and specifications in the			ould satisfy the							
	Humidity Steady State	Appearance	No defects or abno										
		Capacitance	Within ±5% or ±0.										
		Change	(Whichever is large	•				Set the capacitor at 40±2℃ and in 90 to 95% humidity for 500±12 hours.					
		Q	30pF and over: Q≧ 10pF and over, 30 10pF and below: C	pF and below:	Q≧275+5C/2		Remove and set for 24±2 hours at room temperature, t measure.		e, then				
			C: Nominal Capac	itance (pF)									
		I.R.	More than 1,000M Ω										
_													

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Ontinued from the preceding page.

No.	o. Item		Specifications	Test Method			
17			The measured and observed characteristics should satisfy the specifications in the following table.				
	Humidity Load	Appearance	No defects or abnormalities.				
		Capacitance Change	Within ±7.5% or ±0.75pF (Whichever is larger)	Apply the rated voltage at 40 $\pm2^\circ$ C and 90 to 95% humidity for 500 \pm 12 hours. Remove and let sit for 24 \pm 2 hours at room			
.,		Q	30pF and over: Q≥200 30pF and below: Q≥100+10C/3	temperature then measure. The charge/discharge current is less than 50mA.			
			C: Nominal Capacitance (pF)				
		I.R.	More than $500 M\Omega$				
		The measured and observed characteristics should satisfy the specifications in the following table.					
	High Temperature Load	Appearance	No defects or abnormalities.				
		Capacitance Change	Within $\pm 3\%$ or ± 0.3 pF (Whichever is larger)	Apply 200%* of the rated voltage for 1000±12 hours at the maximum operating temperature ±3°C.			
18		Q	30pF and over: Q≥350 10pF and over, 30pF and below: Q≥275+5C/2 10pF and below: Q≥200+10C	Set for 24±2 hours at room temperature, then measure. The charge/discharge current is less than 50mA. *GQM22: 150% of the rated voltage			
			C: Nominal Capacitance (pF)				
		I.R.	More than 1,000MΩ				

Table A

	Nominal Values (ppm/°C) *1	Capacitance Change from 25℃ (%)						
Char.		−55℃		-30℃		-10℃		
		Max.	Min.	Max.	Min.	Max.	Min.	
5C	0±30	0.58	-0.24	0.40	-0.17	0.25	-0.11	

^{*1:} Nominal values denote the temperature coefficient within a range of 25 to 125°C.